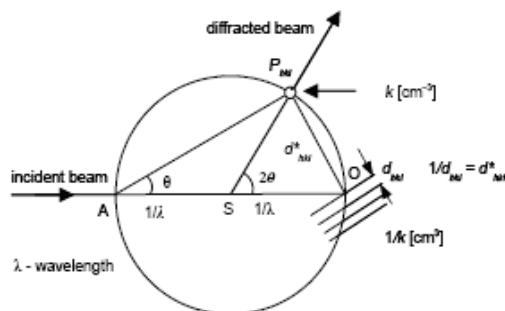


FA3-MS20-P10**An Extinction-Free Technique for Pole Density Measurements of Textures by XRD.** I. Tomov, S.

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Characterisation of textural anisotropy is based on using pole density (texture factor) P that is a quantity normalized in multiples of random distribution of crystallographic orientations [1]. Determining P according to the well-known definition $P=I_{kin}/I_r$ is affected by an extinction-induced systematic error in the measured intensity I_r of the powder standard. Here, I_{kin} is the kinematical intensity of the same reflection of the textured sample, which is corrected for SE [2]. The purpose of this study is to overcome the inherent deficit of accuracy in the above definition and to substantiate a radically novel definition based on the use of empirical extinction coefficient k . It is found that $k=2g\mu/PIOS$ depends on the secondary extinction coefficient g , the linear absorption coefficient μ , the intensity I_0 of the incident X-ray beam and its cross section S [2]. The dimension of k is a reciprocal volume whose value is inversely dependent on the density P of the $\langle hkl \rangle$ poles of the crystal planes contributing to the node $Phkl$ in the reciprocal space as shown in the figure (see [3]). The reciprocal volume corresponding to k is scanned during the measurement of the hkl reflection. According to the relationship between reciprocal and real space, the quantity $1/k$ corresponds to the real space and defines the volume of the crystallites contributing to reflection. In case of randomly orientated crystalline distribution, the pole density P_r is equal to unity. Then, the empirical coefficient kr is expressed by $kr=2g\mu/I_0S$. By dividing the reciprocal quantities $1/k$ and $1/kr$ one obtains the expression $P=kr/k$ for pole density measurements under extinction-free conditions. Whereas this treatment is a simple description of a novel technique, the single reflection method [2] is a proper tool for implementation of this technique for experimental determination of k and kr and, hence, P .



- [1] Bunge, H. J., *Texture Analysis in Materials Science*. London, 1982: Butterworths. [2] Tomov I., *Z. Kristallog. Suppl.*, 2007, 26, 131. [3] Taylor, A., *X-ray Metallography*, John Wiley, New York, 1960.

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